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#### IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Kunihiko HORIKAWA et al.

Conf.

Application No. NEW NATIONAL PHASE

Group

Filed April 26, 2006

Examiner

INFORMATION RECORDING DEVICE AND INFORMATION RECORDING METHOD

# INFORMATION DISCLOSURE STATEMENT (SUBMISSION CONCURRENT WITH THE FILING OF A NEW PATENT APPLICATION)

Assistant Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

April 26, 2006

Sir:

Pursuant to 37 C.F.R. §§ 1.97 and 1.98, and in fulfillment of the duty of disclosure under 37 C.F.R. § 1.56, applicant(s) hereby submit(s) an Information Disclosure Statement for consideration by the Examiner.

### I. LIST OF PATENTS, PUBLICATIONS OR OTHER INFORMATION

The patents, publications, or other information submitted for consideration by the Office are listed on PTO-1449, attached hereto.

#### II. COPIES

- Copies of the U.S. patents or publications are not submitted since the USPTO has waived their submission for applications filed after June 30, 2003.
- Submitted herewith is a legible copy of (i) each foreign patent; (ii) each publication or that portion which caused it to be listed; and (iii) all other information or that portion which caused it to be listed.
- This application is a National Phase of a PCT application. Some or all of the documents listed on the PTO-1449 are not enclosed because they were cited in the International Search Report and copies should have been forwarded from the International Search Authority pursuant to the trilateral agreement between the USPTO, EPO and JPO, or they are U.S. patents or U.S. published applications. If copies are needed, please contact the undersigned.

•• b	Docket No. 8048-1159
	EXPLANATION OF THE RELEVANCE
(check	at least one box) APR 2006
a. 🗌	DOCUMENTS IN THE ENGLISH LANGUAGE
	The attached non U.S. patents, non U.S. patent application publications, foreign publications, or other information in the English language do not require a statement of relevancy.
b. 🛛	DOCUMENTS NOT IN THE ENGLISH LANGUAGE
	A concise explanation of the relevance of all patents, publications, or other information listed that is not in the English language is as follows:
	English Abstracts are provided
c. 🛛	FOREIGN SEARCH REPORT OR ACTION
	An English language version of the search report or action that indicates the degree of relevance found by the foreign office is attached, thereby satisfying the requirement for a concise explanation. See MPEP 609(A)(3).
d. 🗆	OTHER
	The following additional information is provided for the Examiner's consideration.
	<u>FEES</u>
This concurrently therefore, r	Information Disclosure Statement is being filed with the filing of a new patent application; to fee is required.
If The is requested	Examiner has any questions concerning this IDS, he/she to contact the undersigned.
	Respectfully submitted,
	Senoit Castel, Reg. No. 35,041 745 South 23 <sup>rd</sup> Street Arlington, VA 22202 Telephone (703) 521-2297 Telefax (703) 685-0573 (703) 979-4709
BC/tlw	
Enclosures:	<pre></pre>

Other:\_\_\_\_

## INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(Use several sheets if necessary)

Attomey	Docket	No.
0040	44 EQ	

8048-1159

Application No.: **NEW NATIONAL PHASE** 

Applicant: Applicant: Kunihiko HORIKAWA et al.

JU 126 APR 2006

Filing Date:

April 26, 2006

Group Art Unit:

# **U.S. PATENT DOCUMENTS** Examiner **Document Number** Name Class Subclass Filing date Initial (if appropriate) **FOREIGN PATENT DOCUMENTS** Class Subclass Translation Examiner **Document Number** Date Country Initial Yes JP 2003-77128 3/14/2003 **JAPAN** 3/6/1998 JAPAN JP 10-64065 OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) DATE CONSIDERED **EXAMINER:**

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if

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<sup>\*</sup> English language abstract provided for the Examiner's convenience